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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/520,885	BEYER ET AL.	
Examiner	Art Unit	
HIELI T VO	3747	

SEARCHED			
Class	Subclass	Date	Examiner
101	114 112 102 115 99	3/6/2006	VH
123	478 479 494	3/6/2006	VH
73	117.3 116	3/6/2006	VH
73	118.1	3/6/2006	VH
Updated	Search	6/23/2006	VH
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
All of	above	6/24/2006	VH

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	3/6/2006	VH	
EAST (Interference Search)	6/24/2006	VH	
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